



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Kaoru MATSUKI et al.

Group Art Unit: 2877

Application No.: 10/614,203

Filed: July 8, 2003

Docket No.: 116454

For: SURFACE PROFILE MEASURING INSTRUMENT AND SURFACE PROFILE  
MEASURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. The references 1-3 were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully submitted,

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Date: July 13, 2005

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Sheet 1 of 1

Form PTO-1449 (REV. 8-83)			US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 116454		APPLICATION NO. 10/614,203	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)								
			APPLICANTS Kaoru MATSUKI et al.					
			FILING DATE July 8, 2003			GROUP 2877		
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME			CLASS	SUB CLASS
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY			CLASS	SUB CLASS
	1	EP 0 858 015 A1	08/12/1998	EUROPE				
	2	DE 100 00 250 A1	08/31/2000	GERMANY				
	3	DE 100 35 714 A1	07/12/2001	GERMANY				
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>								
<b>EXAMINER</b>							<b>DATE CONSIDERED</b>	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								